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ITC - sigmod In Proceedings of the 6th International Conference On Computer Supported . In Proceedings of the 1999 IEEEuropean Test Workshop (Constance, Germany Jennifer Dworak - SMU M. Sachdev, "Defect Oriented Testing for CMOS Analog and Digital Circuits," . Testing," IEEE International Test Conference, Atlantic City, September 1999, pp. Deep Sub-micron ICs," Proceedings of IEEE International Test Conference, pp.